ASTER announces the first system level PCB viewer integrated with National Instruments TestStand™

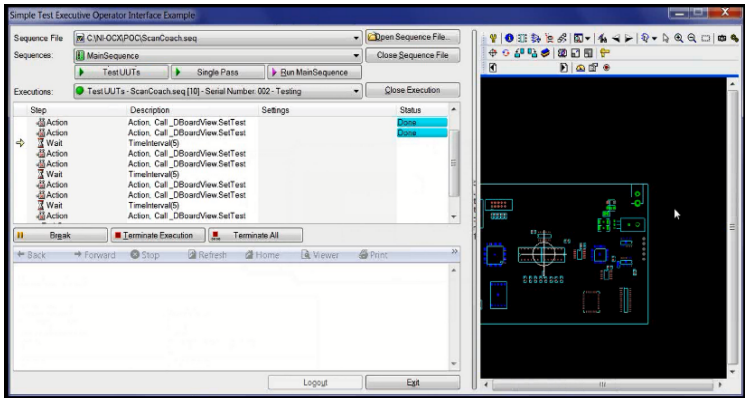
Press Release:

Cesson-Sévigné, FRANCE /Electronica 2016, Munich, 15th – 18th November 2016.

ASTER Technologies, the leading supplier in Board-Level Testability, Test Coverage analysis and Design for Test (DfT) products, announces a revolutionary technology to eliminate functional test inadequacies by integrating **twSystem** within National Instruments TestStand™ and LabView™.

Mr. Christophe LOTZ, President of ASTER Technologies said: "The ability to view PCBA system level connectivity during system level testing is vital in the diagnosis of system level failures."

Functional test solutions are developed, primarily within the hardware design environment, as a test vehicle for verifying that a PCB meets its design criteria. Once the design validation and prototyping test phases are complete, the test vehicle is transferred to the Test Engineering department. It is then used as a functional test platform to verify that manufactured products meet their performance specification and are 'fit for purpose' to be shipped to the customer. The functional test stage is the final PCB quality gate.



The integration of **twSystem** within TestStand™ has the following benefits:

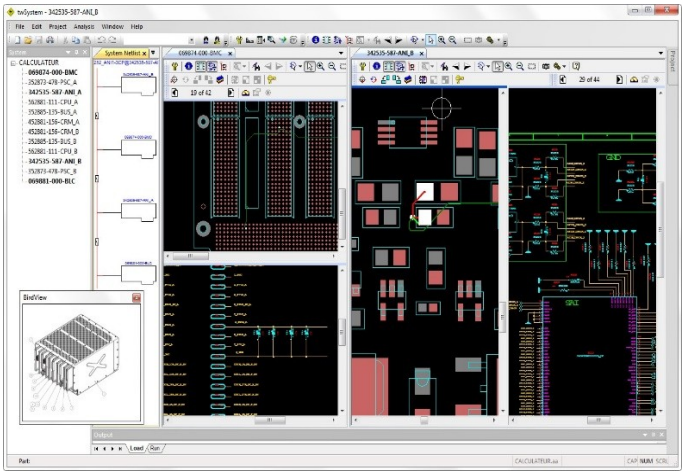
- Reduced test program development & debug using the schematic & virtual schematic views.
- Precise test coverage analysis during functional test development.
- Quick localization of failure/defect on schematic and layout view.
- Accurate diagnosis using the Sherlock algorithm: Overlapping test analysis between functional test steps or between structural tests and functional tests, in eliminating components and circuit networks that are already determined to be fault free.

twSystem™ can be used in the design environment to assist DfT and test coverage analysis at the schematic capture stage as well as during prototype troubleshooting.
Within the manufacturing environment, it becomes an integral part of the repair cycle, assisting in the locating of faults and significantly reducing repair time.

The viewer is designed to import native CAD data for each board comprising the system. In addition, a formal description of the backplane or cables is used to describe the interconnection of the boards. Product performance is a critical issue in order to speed-up loading, viewing, searching and navigation, even when the system includes more than 10 boards with 3000 components on each.

When the CAD data of the system is loaded, **twSystem** delivers various representations of the system.

- List of the boards, backplanes and cables comprising the system. When a board is part of an interconnection, the corresponding connection is highlighted.
- Flat netlist view of the full system, which is the foundation for navigation between interconnecting boards within a system
- Mechanical 3D interactive view of the box, including the boards.
- One window for each active board. Each combining the BOM, schematic diagram and CAD layout.



About ASTER Technologies

ASTER is the leading supplier in Board-Level Testability analysis tools, capitalizing on proven expertise in board testability and strong customer relations. Founded in 1993, ASTER develops a wide range of products dealing with PCB Testability, Viewing and Quality Management. TestWay is a proven solution, used by many PCB design and manufacturing companies worldwide, it provides a unique approach to identifying electrical testability requirements and computing theoretical test coverage, early in the design chain.

For more information, or to get a demonstration of these new features, why not visit ASTER Technologies at booth **352** in **Hall A1** during the Electronica show in Munich between 15th and 18th November, 2016. Alternatively visit www.aster-technologies.com or call +1 719-264-7698.